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Conference Paper	Author(s)	Primary Author Affiliation	IEEE <i>Xplore</i> Paper Citation Count
Particle swarm optimization	J. Kennedy; R. Eberhart	Bureau of Labor Statistics	6,737
Near Shannon limit error-correcting coding and decoding: Turbo-codes. 1	C. Berrou; A. Glavieux; P. Thitimajshima	Ecole Nationale Supérieure des Télécommunications de Bretagne	3,462
Ad-hoc on-demand distance vector routing	C.E. Perkins; E.M. Royer	Sun Microsystems Labs	2,784
Object recognition from local scale-invariant features	D.G. Lowe	University of British Columbia	2,316
A new optimizer using particle swarm theory	R. Eberhart; J. Kennedy	Purdue School of Engineering & Technology	1,848
V-BLAST: an architecture for realizing very high data rates over the rich-scattering wireless channel	P.W. Wolniansky; G.J. Foschini; G.D. Golden; R. Valenzuela	Bell Labs., Lucent Technology	1,740
Adaptive background mixture models for real-time tracking	C. Stauffer; W.E.L. Grimson	Artificial Intelligence Laboratory, MIT	1,682
A modified particle swarm optimizer	Y. Shi; R. Eberhart	Indiana University	1,542
Bilateral filtering for gray and color images	C. Tomasi; R. Manduchi	Stanford University	1,432
Face recognition using eigenfaces	M.A. Turk; A.P. Pentland	Massachusetts Institute of Technology	1,293

Citation counts accurate as of August 2016.

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